

flowSOL 1 BI
650 V/41 mOhm
Features

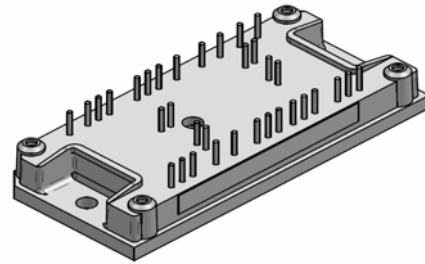
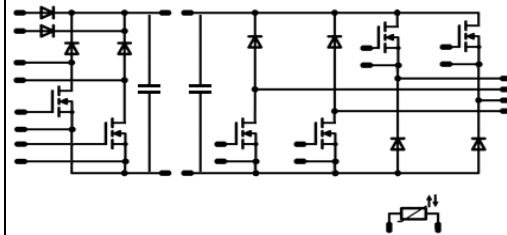
- Low inductive 12mm flow1 package
- Booster:
 - Dual boost topology
 - MOSFET 650V/37mOhm + SiC diode
 - Bypass rectifier
- Inverter:
 - Pseudo H-bridge topology
 - MOSFET 650V/41mOhm CFD + SiC diode
- Integrated DC-capacitors
- Temperature sensor

Target Applications

- Solar Inverter:
- High efficient transformer-less solar inverter with bipolar modulation

Types

10-FY07BIA041MC-M528E58

flow1 12mm housing

Schematic


Maximum Ratings

 $T_j=25^{\circ}\text{C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
-----------	--------	-----------	-------	------

Bypass Diode

Repetitive peak reverse voltage	V_{RRM}		1600	V
Forward current per diode	I_{FAV}	DC current $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	41 55	A
Surge forward current	I_{FSM}	$t_p=10\text{ms}$ $T_j=25^{\circ}\text{C}$	370	A
I^2t -value	I^2t		370	A^2s
Power dissipation per Diode	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	50 76	W
Maximum Junction Temperature	T_{jmax}		150	$^{\circ}\text{C}$

Input Boost MOSFET

Drain to source breakdown voltage	V_{DS}		650	V
DC drain current	I_D	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	35 43	A
Pulsed drain current	I_{Dpulse}	$T_j=25^{\circ}\text{C}$	297	A
Power dissipation	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	105 159	W
Gate-source peak voltage	V_{GS}		± 20	V
Maximum Junction Temperature	T_{jmax}		150	$^{\circ}\text{C}$

Maximum Ratings

 $T_j=25^{\circ}\text{C}$, unless otherwise specified

Parameter	Symbol	Condition	Value	Unit
-----------	--------	-----------	-------	------

Input Boost Diode

Peak Repetitive Reverse Voltage	V_{RRM}	$T_j=25^{\circ}\text{C}$	650	V
DC forward current	I_F	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	22 28	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	134	A
Power dissipation	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	48 73	W
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

Pseudo H-Bridge MOSFET

Drain to source breakdown voltage	V_{DS}		650	V
DC drain current	I_D	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	34 42	A
Pulsed drain current	I_{Dpulse}	t_p limited by T_{jmax} $T_c=25^{\circ}\text{C}$	255	A
Power dissipation	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	111 168	W
Gate-source peak voltage	V_{gs}		± 20	V
Maximum Junction Temperature	T_{jmax}		150	$^{\circ}\text{C}$

Pseudo H-Bridge Diode

Peak Repetitive Reverse Voltage	V_{RRM}	$T_j=25^{\circ}\text{C}$	650	V
DC forward current	I_F	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	22 29	A
Repetitive peak forward current	I_{FRM}	t_p limited by T_{jmax}	134	A
Power dissipation per Diode	P_{tot}	$T_j=T_{jmax}$ $T_h=80^{\circ}\text{C}$ $T_c=80^{\circ}\text{C}$	48 73	W
Maximum Junction Temperature	T_{jmax}		175	$^{\circ}\text{C}$

DC link Capacitor

Max.DC voltage	V_{MAX}	$T_c=25^{\circ}\text{C}$	630	V
----------------	-----------	--------------------------	-----	---

Thermal Properties

Storage temperature	T_{stg}		-40...+125	$^{\circ}\text{C}$
Operation temperature under switching condition	T_{op}		-40...+($T_{jmax} - 25$)	$^{\circ}\text{C}$

Insulation Properties

Insulation voltage	V_{is}	$t=2s$ DC voltage	4000	V
Creepage distance			min 12,7	mm
Clearance			min 12,7	mm

Characteristic Values

Parameter	Symbol	Conditions					Value			Unit
			V _{GE} [V] or V _{GS} [V]	V _r [V] or V _{CE} [V] or V _{DS} [V]	I _C [A] or I _F [A] or I _o [A]	T _j	Min	Typ	Max	
Bypass Diode										
Forward voltage	solar invert				35	T _j =25°C T _j =125°C		1.18 1.17	1.21	V
Threshold voltage (for power loss calc. only)	V _{to}				35	T _j =25°C T _j =125°C		0.91 0.80		V
Slope resistance (for power loss calc. only)	r _t				35	T _j =25°C T _j =125°C		0.01 0.01		Ω
Reverse current	I _r			1600		T _j =25°C T _j =125°C			0.05	mA
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal grease thickness≤50um						1.40		K/W
Thermal resistance chip to case per chip	R _{thJC}	λ = 1 W/mK						0.92		
Input Boost MOSFET										
Static drain to source ON resistance	R _{DS(on)}		10		50	T _j =25°C T _j =125°C		38 78		mΩ
Gate threshold voltage	V _{(GS)th}				0.0033	T _j =25°C T _j =125°C	2.5	3	3.5	V
Gate to Source Leakage Current	I _{gss}		20	0		T _j =25°C T _j =125°C			100	nA
Zero Gate Voltage Drain Current	I _{dss}		0	650		T _j =25°C T _j =125°C			2000	nA
Turn On Delay Time	t _{d(ON)}	Rgoff=2 Ω Rgon=2 Ω	10	400	30	T _j =25°C T _j =125°C		30 29		ns
Rise Time	t _r					T _j =25°C T _j =125°C		6 7		
Turn off delay time	t _{d(OFF)}					T _j =25°C T _j =125°C		173 186		
Fall time	t _f					T _j =25°C T _j =125°C		6 7		
Turn-on energy loss per pulse	E _{on}					T _j =25°C T _j =125°C		0.11 0.12		
Turn-off energy loss per pulse	E _{off}	T _j =25°C T _j =125°C		0.04 0.06						
Total gate charge	Q _g	Rgon=2 Ω	10	480	49.6	T _j =25°C T _j =125°C		330		nC
Gate to source charge	Q _{gs}					T _j =25°C T _j =125°C		40		
Gate to drain charge	Q _{gd}					T _j =25°C T _j =125°C		170		
Input capacitance	C _{iss}	f=1MHz	0	100		T _j =25°C		7240		pF
Output capacitance	C _{oss}							380		
Reverse transfer capacitance	C _{rss}							tbd.		
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal grease thickness≤50um						0.67		K/W
Thermal resistance chip to case per chip	R _{thJC}	λ = 1 W/mK						0.44		
Input Boost Diode										
Forward voltage	V _F				20	T _j =25°C T _j =125°C		1.61 1.86	1.8	V
Reverse leakage current	I _{rm}		10	400	30	T _j =25°C T _j =125°C			60	μA
Peak recovery current	I _{RRM}	Rgon=2 Ω	10	400	30	T _j =25°C T _j =125°C		25 23		A
Reverse recovery time	t _{rr}					T _j =25°C T _j =125°C		9 11		ns
Reverse recovery charge	Q _{rr}					T _j =25°C T _j =125°C		0.19 0.26		μC
Reverse recovered energy	E _{rec}					T _j =25°C T _j =125°C		0.05 0.07		mWs
Peak rate of fall of recovery current	di(rec)max /dt									T _j =25°C T _j =125°C
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal grease thickness≤50um						1.98		K/W
Thermal resistance chip to case per chip	R _{thJC}	λ = 1 W/mK						1.31		

Characteristic Values

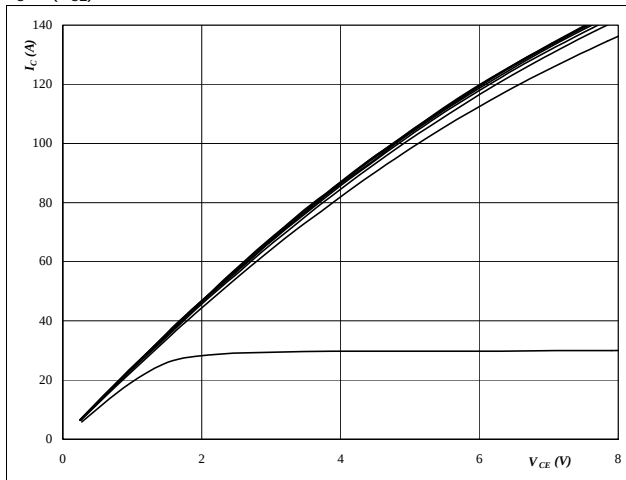
Parameter	Symbol	Conditions					Value			Unit
			V _{GE} [V] or V _{GS} [V]	V _r [V] or V _{CE} [V] or V _{DS} [V]	I _c [A] or I _F [A] or I _b [A]	T _j	Min	Typ	Max	
Pseudo H-Bridge MOSFET										
Static drain to source ON resistance	R _{ds(on)}		10		50	T _j =25°C T _j =125°C		43 80		mΩ
Gate threshold voltage	V _{(GS)th}			V _{DS} =V _{GS}	0.0033	T _j =25°C T _j =125°C	3.5	4	4.5	V
Gate to Source Leakage Current	I _{gss}		20	0		T _j =25°C T _j =125°C			100	nA
Zero Gate Voltage Drain Current	I _{dss}		0	650		T _j =25°C T _j =125°C			3500	nA
Turn On Delay Time	t _{d(ON)}	Rgoff=2 Ω Rgon=2 Ω	10	400	30	T _j =25°C T _j =125°C		37 36		ns
Rise Time	t _r					T _j =25°C T _j =125°C		6 7		
Turn off delay time	t _{d(OFF)}					T _j =25°C T _j =125°C		146 154		
Fall time	t _f					T _j =25°C T _j =125°C		7 4		
Turn-on energy loss per pulse	E _{on}					T _j =25°C T _j =125°C		0.12 0.14		mWs
Turn-off energy loss per pulse	E _{off}					T _j =25°C T _j =125°C		0.03 0.04		
Total gate charge	Q _g		10	480	49.6	T _j =25°C		300		nC
Gate to source charge	Q _{gs}							54		
Gate to drain charge	Q _{gd}							165		
Input capacitance	C _{iss}	f=1MHz	0	100		T _j =25°C		8400		pF
Output capacitance	C _{oss}							400		
Reverse transfer capacitance	C _{rss}							tbd.		
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal grease thickness≤50um λ = 1 W/mK						0.63		K/W
Thermal resistance chip to case per chip	R _{thJC}						0.42			
Pseudo H-Bridge Diode										
Diode forward voltage	V _F				50	T _j =25°C T _j =125°C		1.61 1.85	1.8	V
Peak reverse recovery current	I _{RRM}	Rgon=2 Ω	15	400	60	T _j =25°C T _j =125°C		27 24		A
Reverse recovery time	t _{rr}					T _j =25°C T _j =125°C		10 10		ns
Reverse recovered charge	Q _{rr}					T _j =25°C T _j =125°C		0.19 0.20		μC
Peak rate of fall of recovery current	di(rec)max /dt					T _j =25°C T _j =125°C		7041 5575		A/μs
Reverse recovery energy	E _{rec}					T _j =25°C T _j =125°C		0.04 0.05		mWs
Thermal resistance chip to heatsink per chip	R _{thJH}	Thermal grease thickness≤50um λ = 1 W/mK						1.98		K/W
Thermal resistance chip to case per chip	R _{thJC}						1.31			
DC link Capacitor										
C value	C							47		nF
Thermistor										
Rated resistance	R					T _j =25°C		22000		Ω
Deviation of R25	ΔR/R	R100=1486 Ω				T _c =100°C	-5		+5	%
Power dissipation	P					T _c =100°C		200		mW
Power dissipation constant						T _j =25°C		2		mW/K
B-value	B _(25/50)	Tol. ±3%				T _j =25°C		3950		K
B-value	B _(25/100)	Tol. ±3%				T _j =25°C		3996		K
Vincotech NTC Reference						T _j =25°C			B	

Pseudo H-Bridge

Figure 1 MOSFET

Typical output characteristics

$$I_C = f(V_{CE})$$



At

$t_p = 250 \mu s$
 $T_J = 25 ^\circ C$
 V_{GE} from 0 V to 20 V in steps of 2 V

Figure 2 MOSFET

Typical output characteristics

$$I_C = f(V_{CE})$$



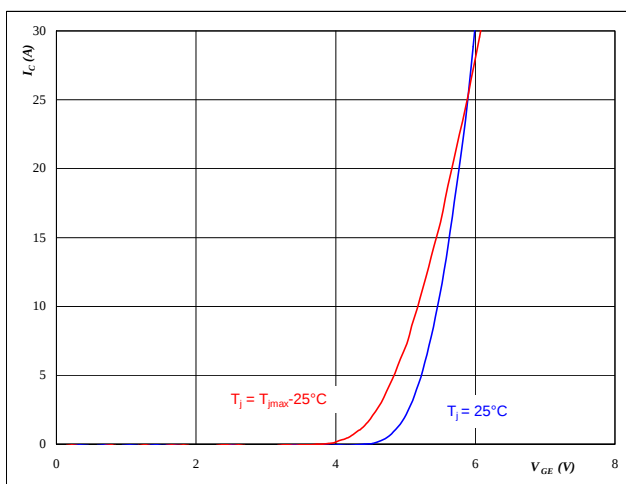
At

$t_p = 250 \mu s$
 $T_J = 125 ^\circ C$
 V_{GE} from 0 V to 20 V in steps of 2 V

Figure 3 MOSFET

Typical transfer characteristics

$$I_C = f(V_{GE})$$



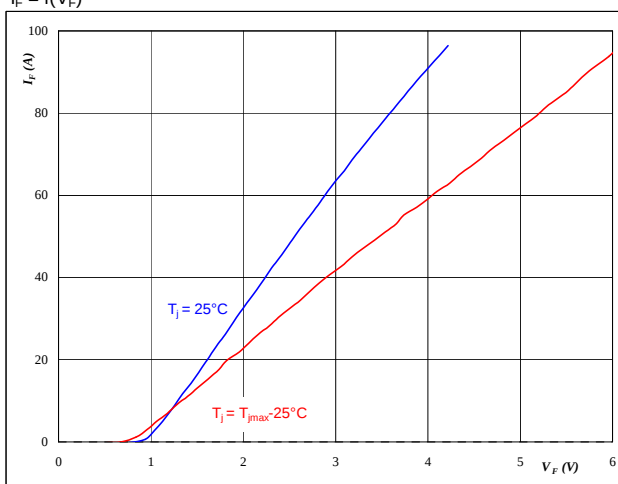
At

$t_p = 250 \mu s$
 $V_{CE} = 10 V$

Figure 4 FWD

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$



At

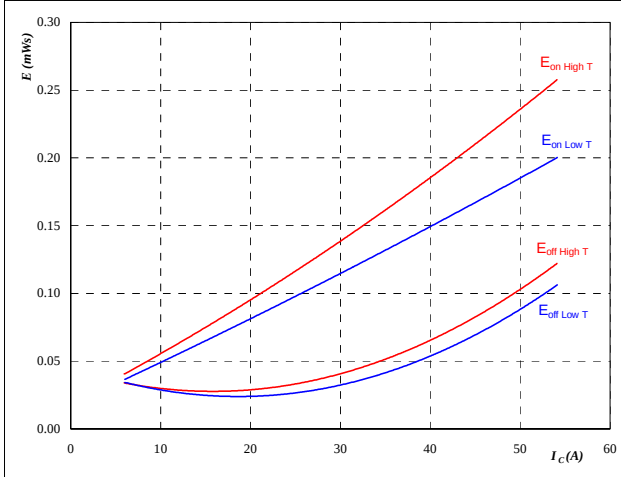
$t_p = 250 \mu s$

Pseudo H-Bridge

Figure 5 MOSFET

Typical switching energy losses
as a function of collector current

$$E = f(I_C)$$



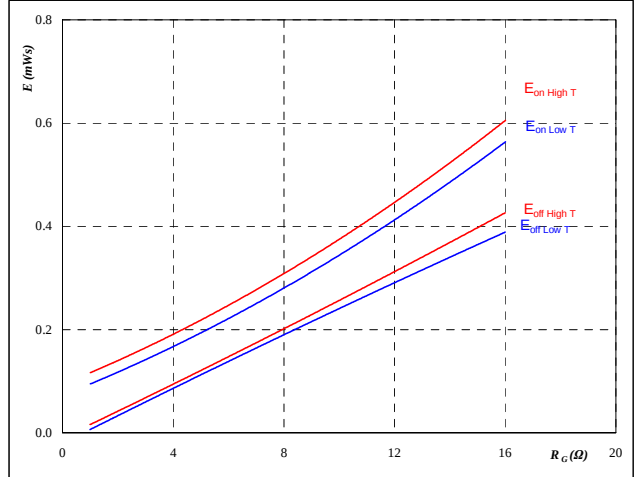
With an inductive load at

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω
$R_{goff} =$	2	Ω

Figure 6 MOSFET

Typical switching energy losses
as a function of gate resistor

$$E = f(R_G)$$



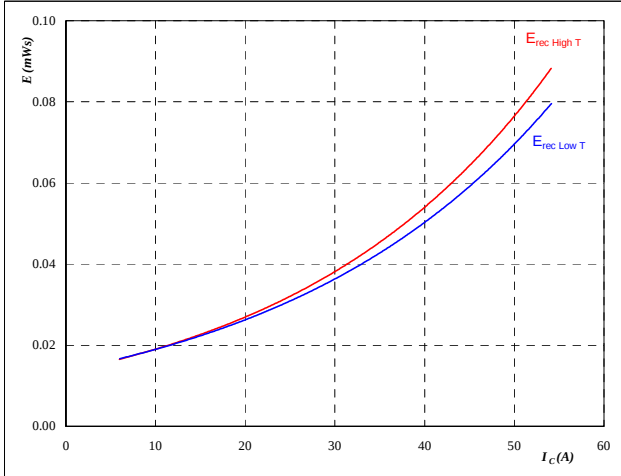
With an inductive load at

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$I_C =$	30	A

Figure 7 FWD

Typical reverse recovery energy loss
as a function of collector current

$$E_{rec} = f(I_C)$$



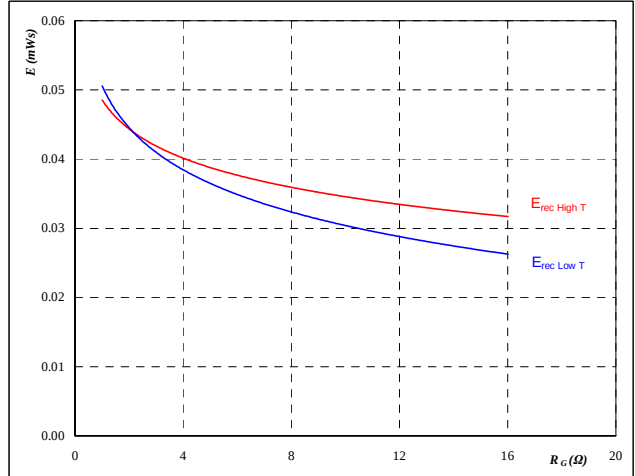
With an inductive load at

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 8 FWD

Typical reverse recovery energy loss
as a function of gate resistor

$$E_{rec} = f(R_G)$$



With an inductive load at

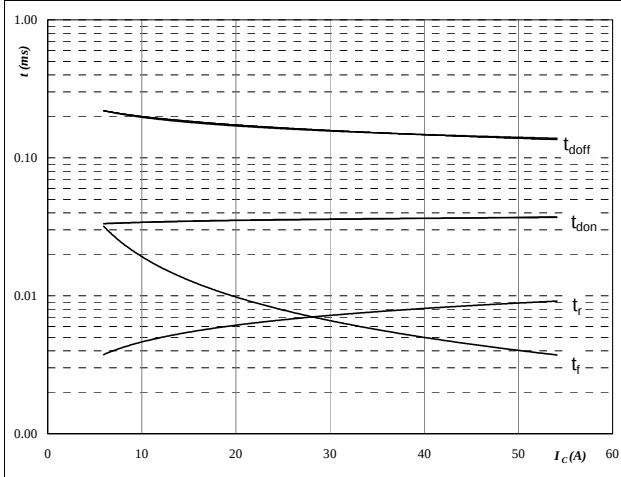
$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$I_C =$	30	A

Pseudo H-Bridge

Figure 9 MOSFET

Typical switching times as a function of collector current

$$t = f(I_C)$$



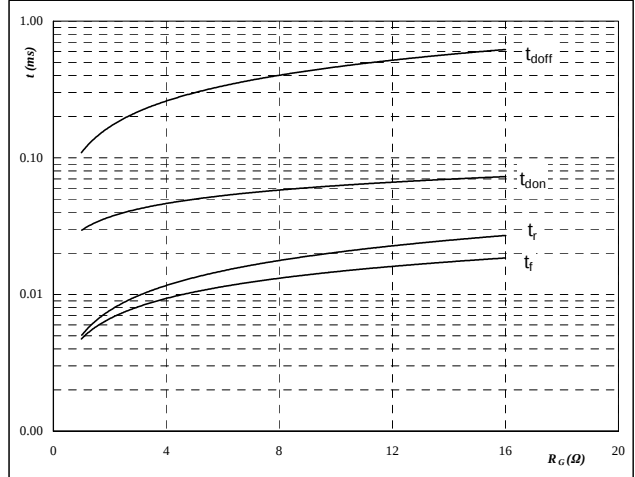
With an inductive load at

$T_J =$	125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω
$R_{goff} =$	2	Ω

Figure 10 MOSFET

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



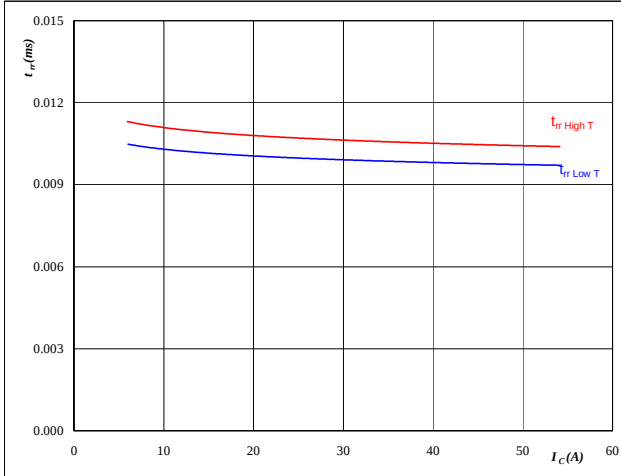
With an inductive load at

$T_J =$	125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$I_C =$	30	A

Figure 11 FWD

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



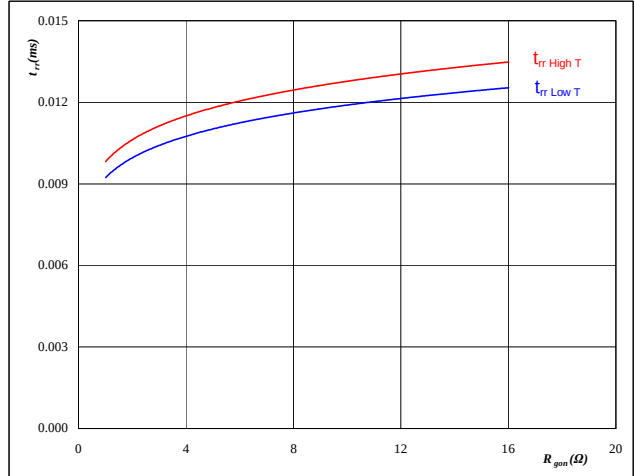
At

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 12 FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{gon})$$



At

$T_J =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GE} =$	10	V

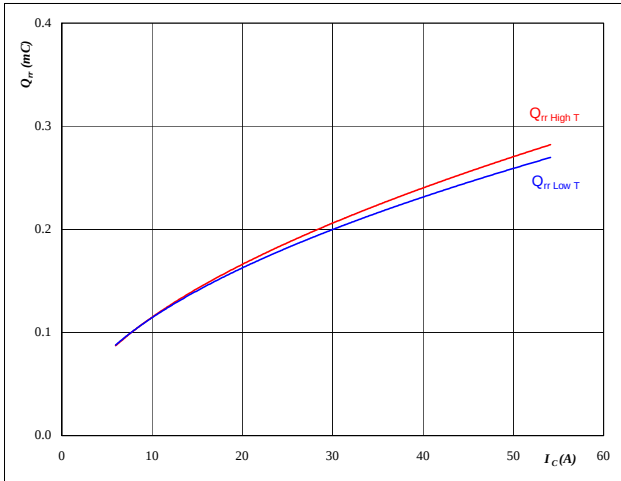
Pseudo H-Bridge

Figure 13

FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$



At

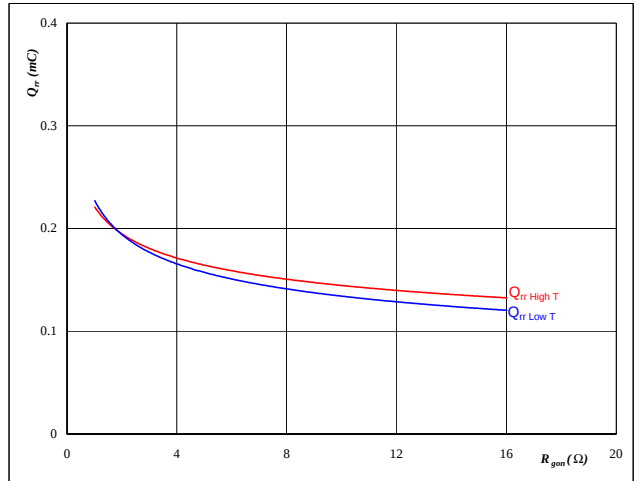
$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 14

FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$



At

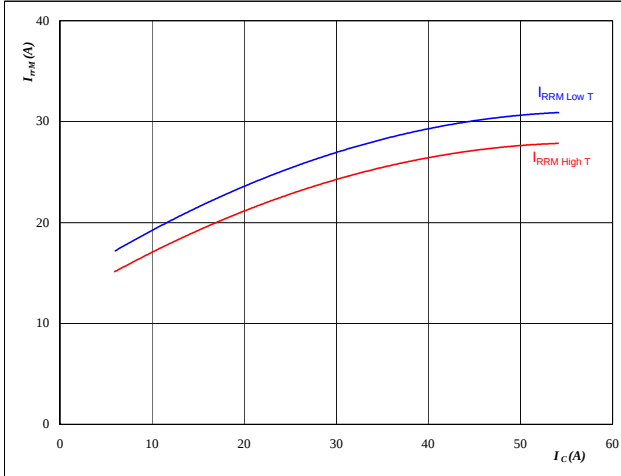
$T_J =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GE} =$	10	V

Figure 15

FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$



At

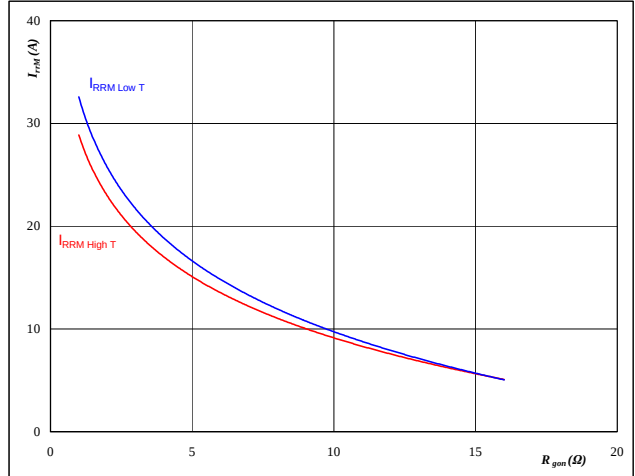
$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 16

FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At

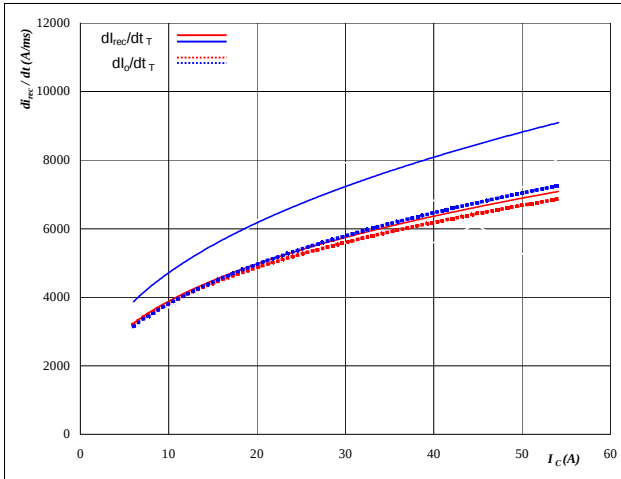
$T_J =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GE} =$	10	V

Pseudo H-Bridge

Figure 17 FWD

Typical rate of fall of forward
and reverse recovery current as a
function of collector current

$$di_o/dt, di_{rec}/dt = f(I_c)$$

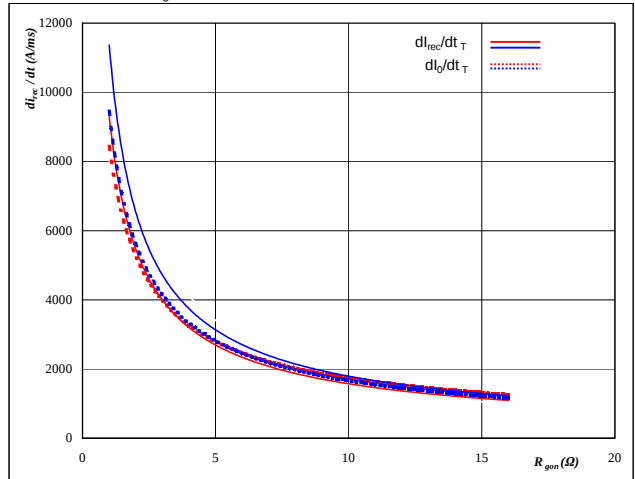


At
T_J = 25/125 °C
V_{CE} = 400 V
V_{GE} = 10 V
R_{gon} = 2 Ω

Figure 18 FWD

Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor

$$di_o/dt, di_{rec}/dt = f(R_{gon})$$

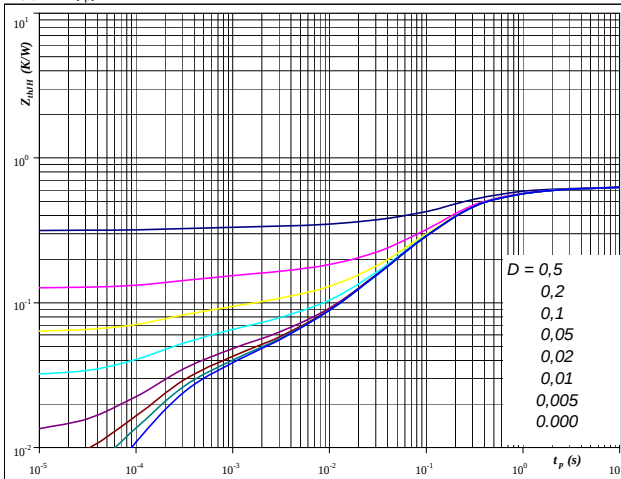


At
T_J = 25/125 °C
V_R = 400 V
I_F = 30 A
V_{GE} = 10 V

Figure 19 MOSFET

IGBT transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At
D = t_p / T
R_{thJH} = 0.63 K/W

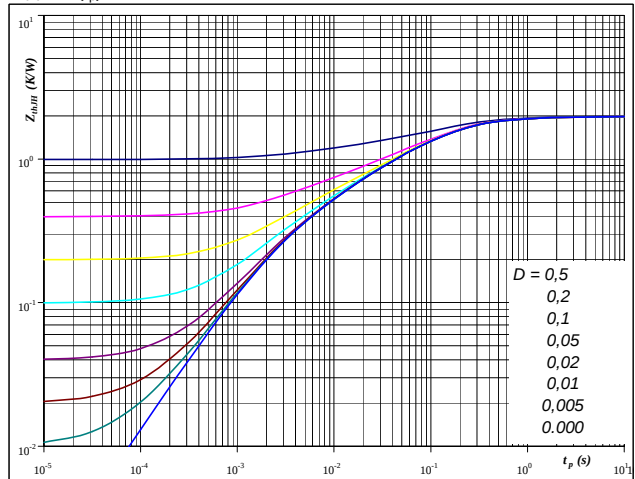
IGBT thermal model values

R (C/W)	Tau (s)
0.04	5.1E+00
0.08	1.0E+00
0.30	2.1E-01
0.14	8.6E-02
0.03	1.3E-02
0.02	1.4E-03

Figure 20 FWD

FWD transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At
D = t_p / T
R_{thJH} = 1.98 K/W

FWD thermal model values

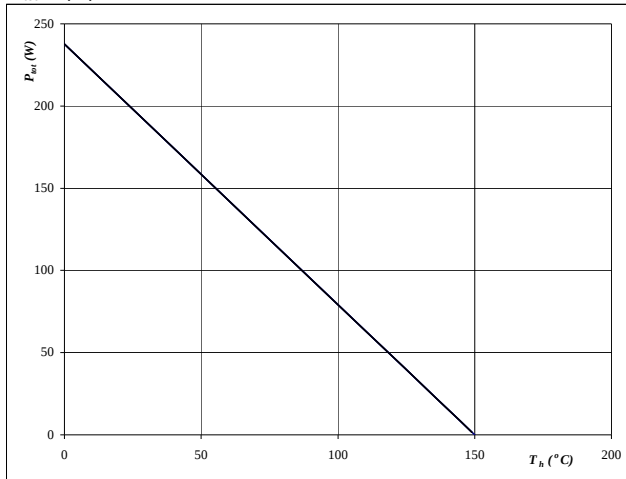
R (C/W)	Tau (s)
0.06	3.9E+00
0.15	7.0E-01
0.84	1.5E-01
0.44	4.4E-02
0.33	9.5E-03
0.17	2.0E-03

Pseudo H-Bridge

Figure 21 MOSFET

Power dissipation as a function of heatsink temperature

$$P_{\text{tot}} = f(T_h)$$

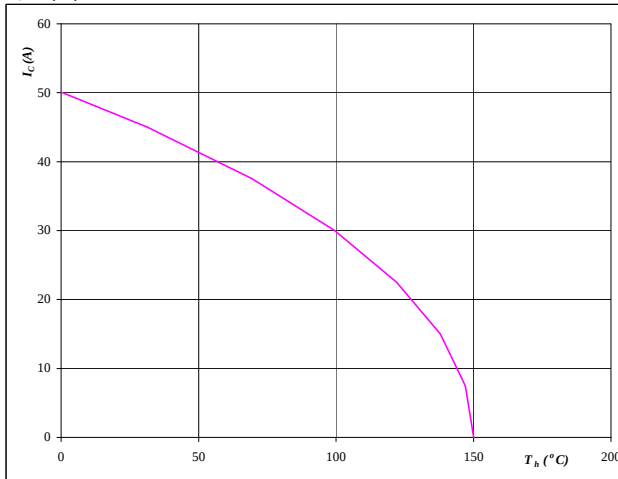


At
 $T_j = 150$ °C

Figure 22 MOSFET

Collector current as a function of heatsink temperature

$$I_C = f(T_h)$$

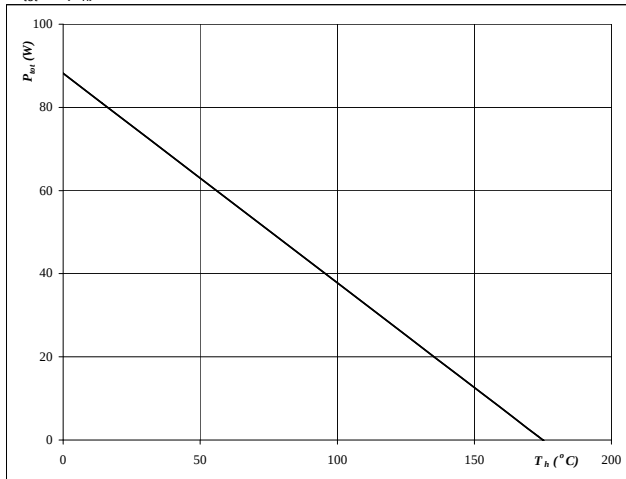


At
 $T_j = 150$ °C
 $V_{GE} = 15$ V

Figure 23 FWD

Power dissipation as a function of heatsink temperature

$$P_{\text{tot}} = f(T_h)$$

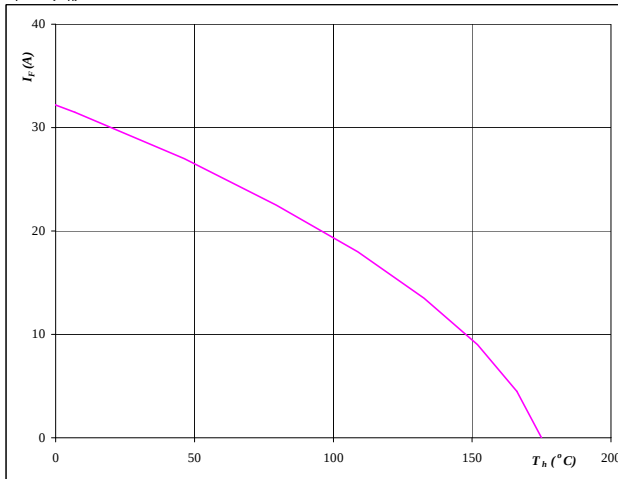


At
 $T_j = 175$ °C

Figure 24 FWD

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



At
 $T_j = 175$ °C

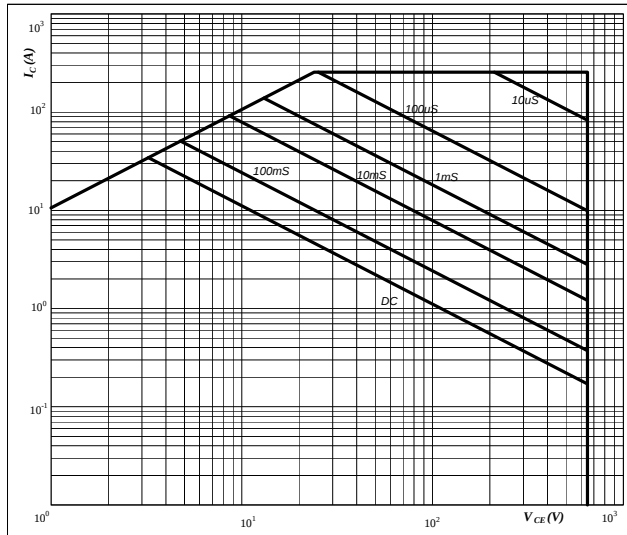
Pseudo H-Bridge

Figure 25

MOSFET

Safe operating area as a function
of collector-emitter voltage

$$I_C = f(V_{CE})$$



At

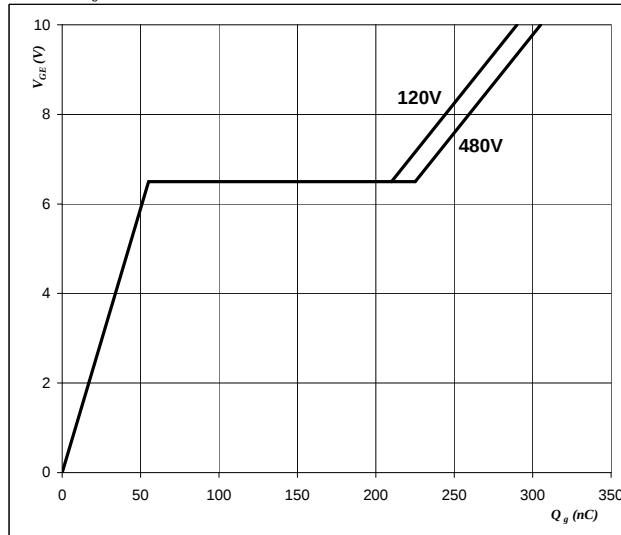
D = single pulse
Th = 80 °C
V_{GE} = 15 V
T_J = T_{Jmax} °C

Figure 26

MOSFET

Gate voltage vs Gate charge

$$V_{GE} = f(Q_g)$$



At

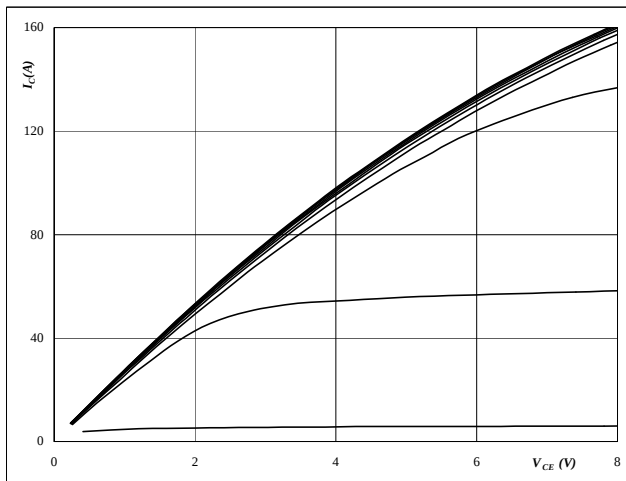
I_C = 50 A

INPUT BOOST

Figure 1 BOOST MOSFET

Typical output characteristics

$$I_D = f(V_{DS})$$

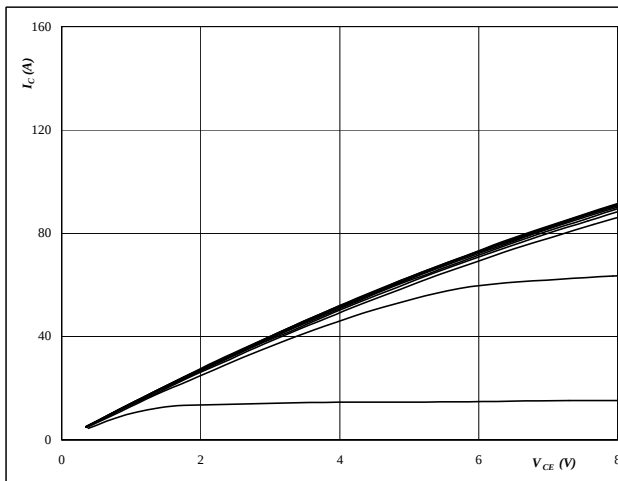


At
 $t_p = 250 \mu s$
 $T_J = 25^\circ C$
 V_{GS} from 3 V to 13 V in steps of 1 V

Figure 2 BOOST MOSFET

Typical output characteristics

$$I_D = f(V_{DS})$$

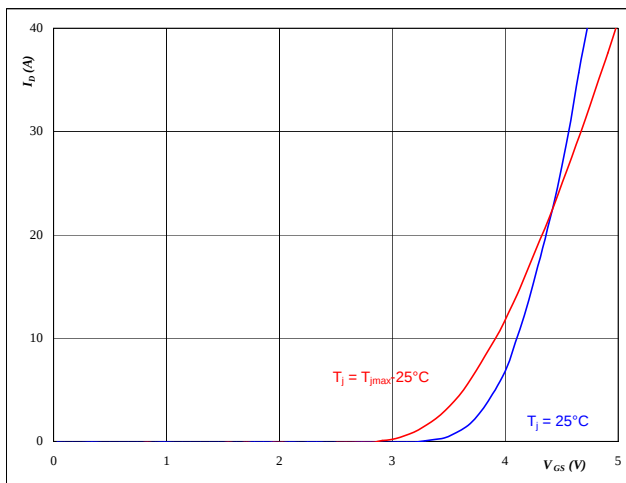


At
 $t_p = 250 \mu s$
 $T_J = 125^\circ C$
 V_{GS} from 3 V to 13 V in steps of 1 V

Figure 3 BOOST MOSFET

Typical transfer characteristics

$$I_D = f(V_{GS})$$

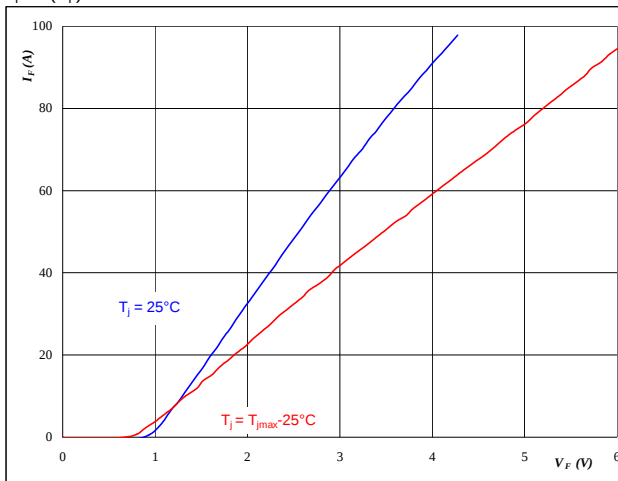


At
 $t_p = 250 \mu s$
 $V_{DS} = 10 V$

Figure 4 BOOST FWD

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$



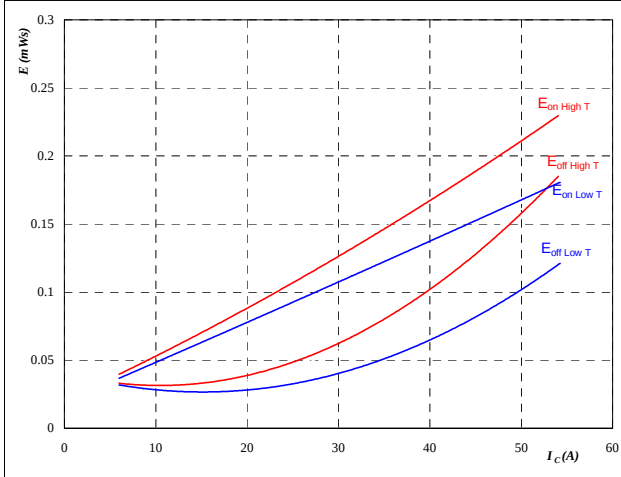
At
 $t_p = 250 \mu s$

INPUT BOOST

Figure 5 BOOST MOSFET

Typical switching energy losses
as a function of collector current

$$E = f(I_D)$$



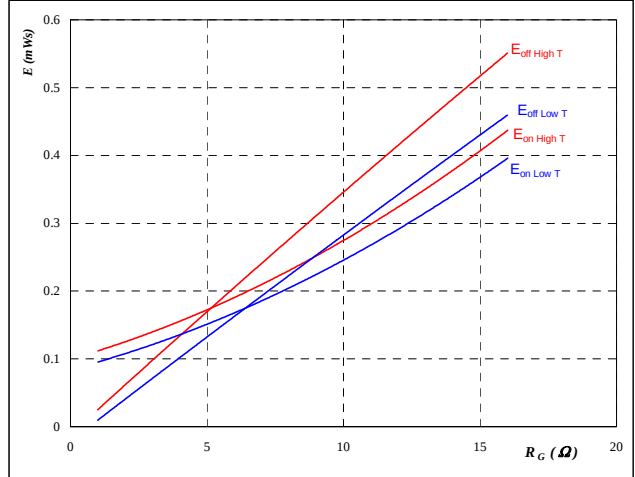
With an inductive load at

$T_J = 25/125$ °C
 $V_{DS} = 400$ V
 $V_{GS} = 10$ V
 $R_{gon} = 2$ Ω
 $R_{goff} = 2$ Ω

Figure 6 BOOST MOSFET

Typical switching energy losses
as a function of gate resistor

$$E = f(R_G)$$



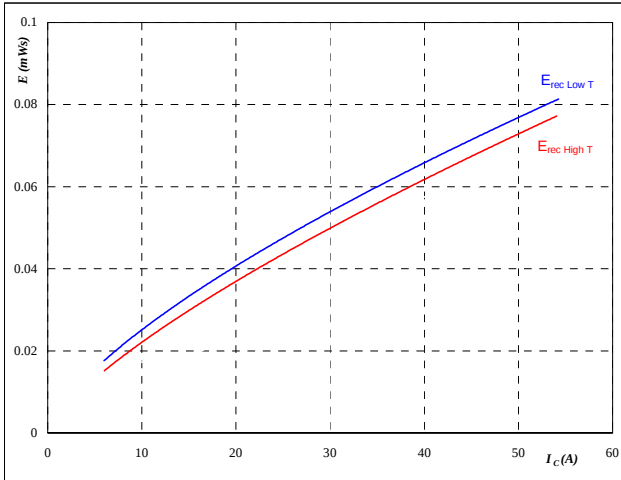
With an inductive load at

$T_J = 25/125$ °C
 $V_{DS} = 400$ V
 $V_{GS} = 10$ V
 $I_D = 30$ A

Figure 7 BOOST FWD

Typical reverse recovery energy loss
as a function of collector (drain) current

$$E_{rec} = f(I_C)$$



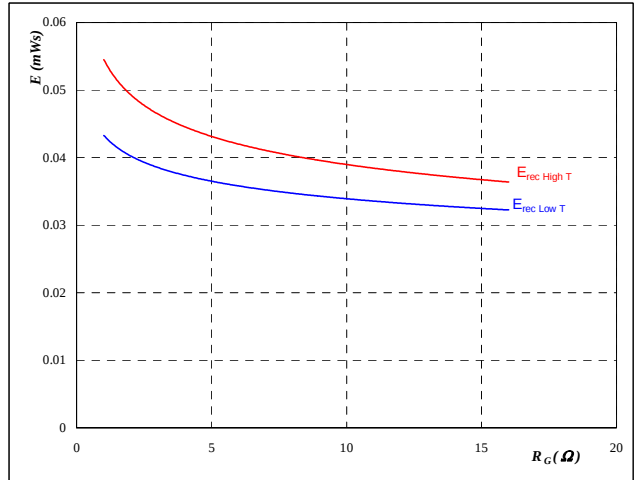
With an inductive load at

$T_J = 25/125$ °C
 $V_{DS} = 400$ V
 $V_{GS} = 10$ V
 $R_{gon} = 2$ Ω
 $R_{goff} = 2$ Ω

Figure 8 BOOST FWD

Typical reverse recovery energy loss
as a function of gate resistor

$$E_{rec} = f(R_G)$$



With an inductive load at

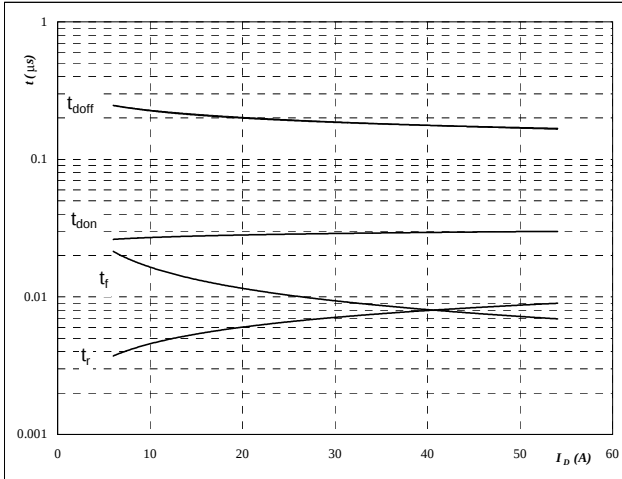
$T_J = 25/125$ °C
 $V_{DS} = 400$ V
 $V_{GS} = 10$ V
 $I_D = 30$ A

INPUT BOOST

Figure 9 BOOST MOSFET

Typical switching times as a function of collector current

$$t = f(I_D)$$



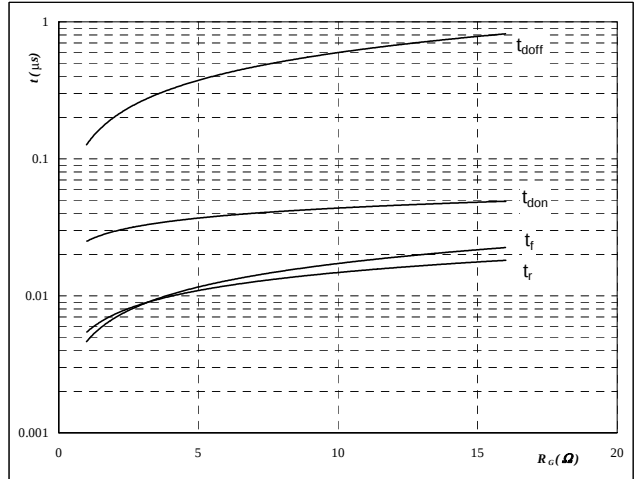
With an inductive load at

$T_J =$	125	°C
$V_{DS} =$	400	V
$V_{GS} =$	10	V
$R_{gon} =$	2	Ω
$R_{goff} =$	2	Ω

Figure 10 BOOST MOSFET

Typical switching times as a function of gate resistor

$$t = f(R_G)$$



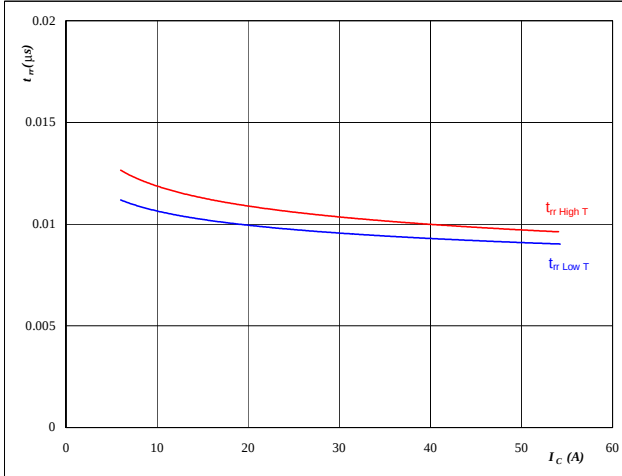
With an inductive load at

$T_J =$	125	°C
$V_{DS} =$	400	V
$V_{GS} =$	10	V
$I_C =$	30	A

Figure 11 BOOST FWD

Typical reverse recovery time as a function of collector current

$$t_{rr} = f(I_C)$$



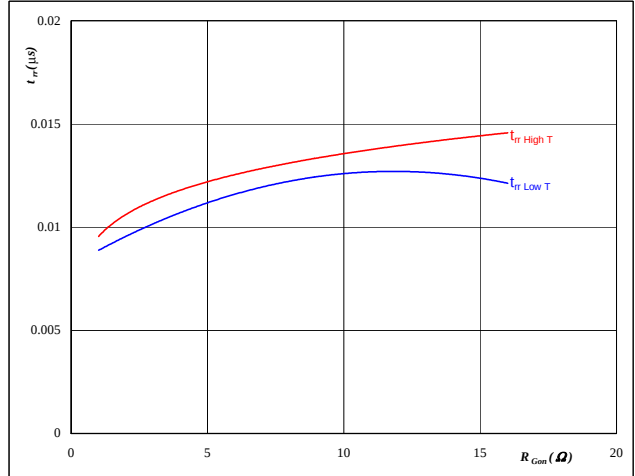
At

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 12 BOOST FWD

Typical reverse recovery time as a function of IGBT turn on gate resistor

$$t_{rr} = f(R_{gon})$$



At

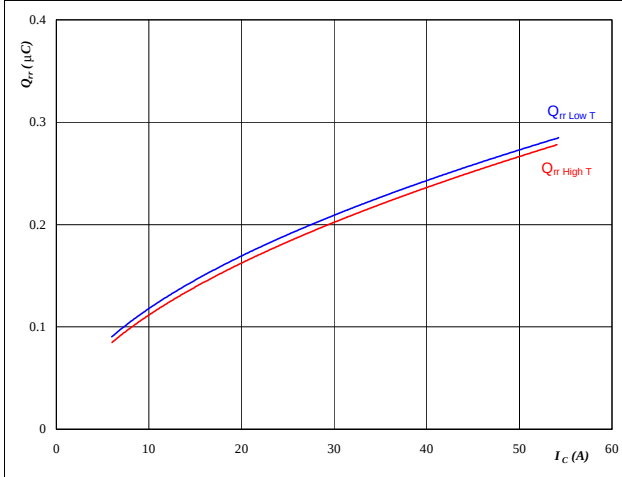
$T_J =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GS} =$	10	V

INPUT BOOST

Figure 13 BOOST FWD

Typical reverse recovery charge as a function of collector current

$$Q_{rr} = f(I_C)$$



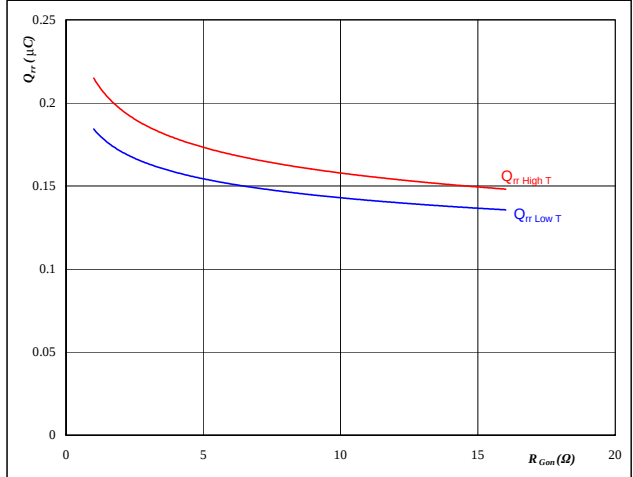
At

$T_j =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 14 BOOST FWD

Typical reverse recovery charge as a function of IGBT turn on gate resistor

$$Q_{rr} = f(R_{gon})$$



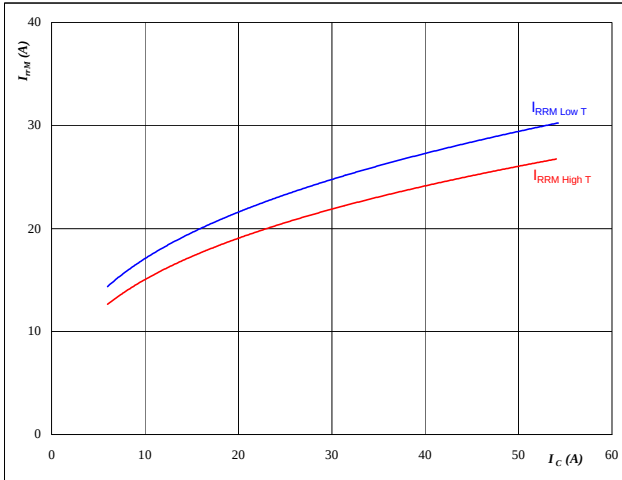
At

$T_j =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GS} =$	10	V

Figure 15 BOOST FWD

Typical reverse recovery current as a function of collector current

$$I_{RRM} = f(I_C)$$



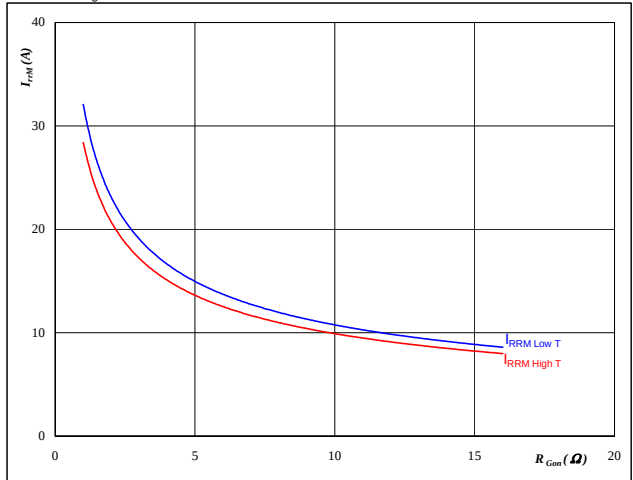
At

$T_j =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 16 BOOST FWD

Typical reverse recovery current as a function of IGBT turn on gate resistor

$$I_{RRM} = f(R_{gon})$$



At

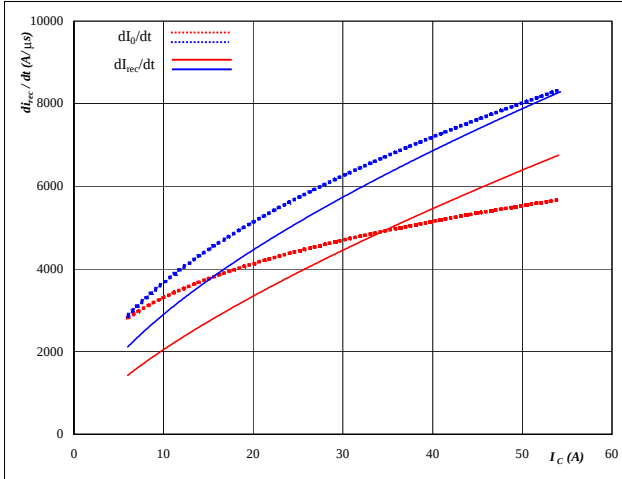
$T_j =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GS} =$	10	V

INPUT BOOST

Figure 17 BOOST FWD

Typical rate of fall of forward
and reverse recovery current as a
function of collector current

$$dI_F/dt, dI_{rec}/dt = f(I_C)$$



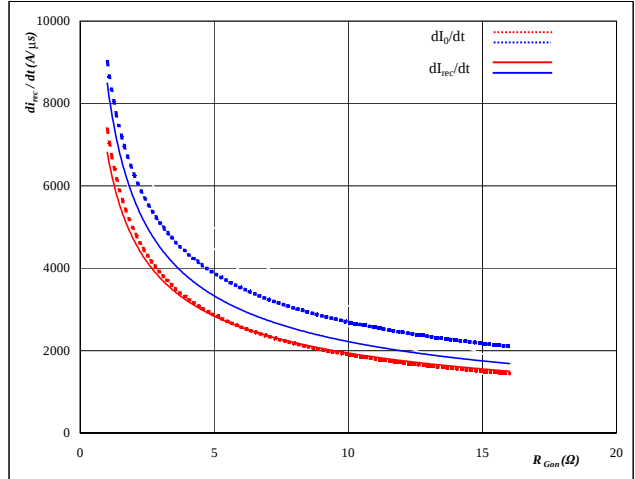
At

$T_J =$	25/125	°C
$V_{CE} =$	400	V
$V_{GE} =$	10	V
$R_{gon} =$	2	Ω

Figure 18 BOOST FWD

Typical rate of fall of forward
and reverse recovery current as a
function of IGBT turn on gate resistor

$$dI_F/dt, dI_{rec}/dt = f(R_{gon})$$



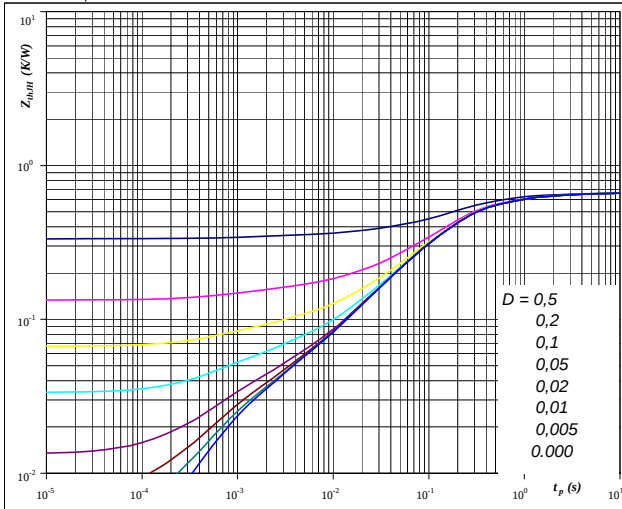
At

$T_J =$	25/125	°C
$V_R =$	400	V
$I_F =$	30	A
$V_{GS} =$	10	V

Figure 19 BOOST MOSFET

IGBT/MOSFET transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At

$D =$	t_p / T	
$R_{thJH} =$	0.67	K/W

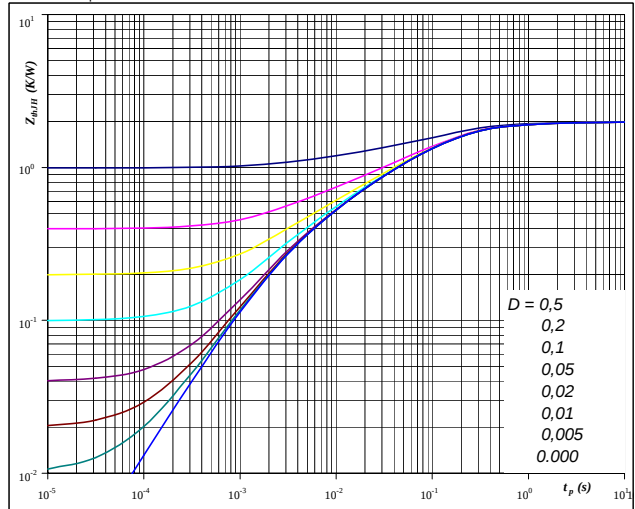
IGBT thermal model values

R (C/W)	Tau (s)
3.56E-02	5.26E+00
8.98E-02	9.94E-01
3.76E-01	1.88E-01
1.04E-01	6.08E-02
3.74E-02	1.20E-02
2.56E-02	9.33E-04

Figure 20 BOOST FWD

FWD transient thermal impedance
as a function of pulse width

$$Z_{thJH} = f(t_p)$$



At

$D =$	t_p / T	
$R_{thJH} =$	1.98	K/W

FWD thermal model values

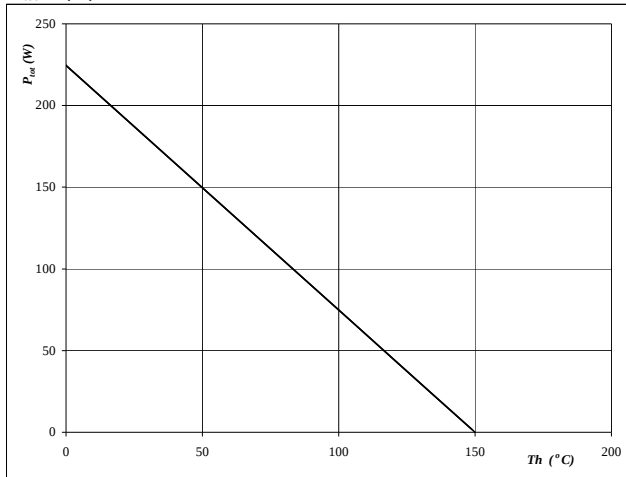
R (C/W)	Tau (s)
5.95E-02	3.91E+00
1.47E-01	7.03E-01
8.44E-01	1.45E-01
4.42E-01	4.35E-02
3.26E-01	9.54E-03
1.67E-01	2.01E-03

INPUT BOOST

Figure 21 BOOST MOSFET

Power dissipation as a
function of heatsink temperature

$$P_{\text{tot}} = f(T_h)$$

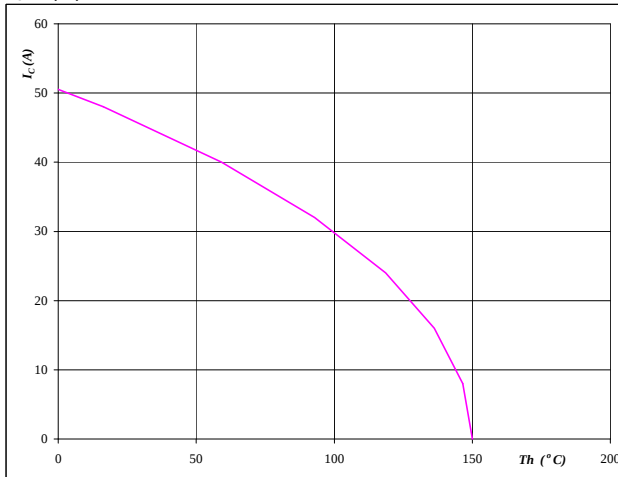


At
 $T_j = 150$ °C

Figure 22 BOOST MOSFET

Collector/Drain current as a
function of heatsink temperature

$$I_C = f(T_h)$$

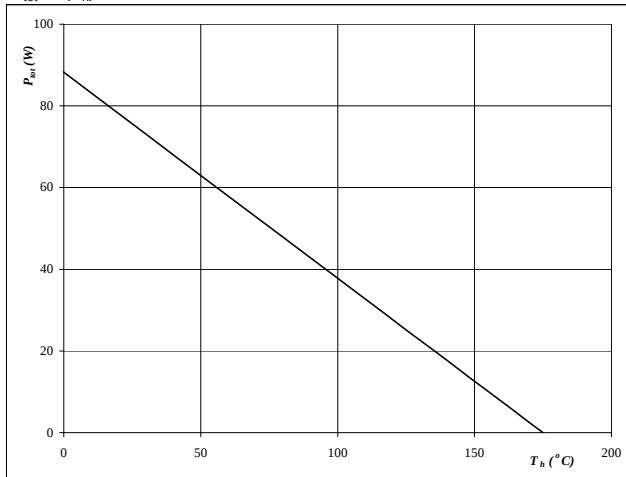


At
 $T_j = 150$ °C
 $V_{GS} = 10$ V

Figure 23 BOOST FWD

Power dissipation as a
function of heatsink temperature

$$P_{\text{tot}} = f(T_h)$$

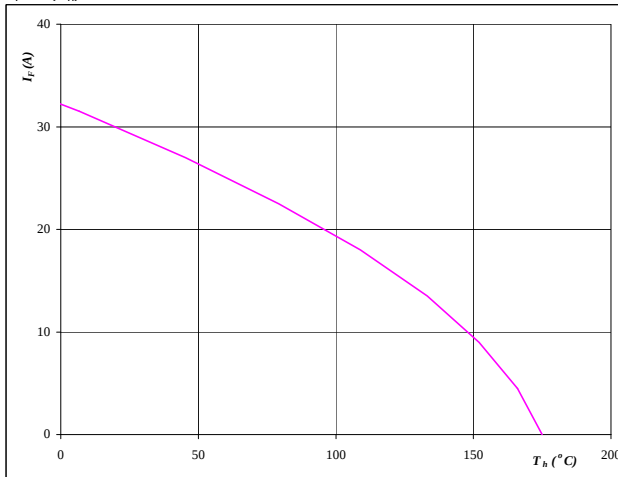


At
 $T_j = 175$ °C

Figure 24 BOOST FWD

Forward current as a
function of heatsink temperature

$$I_F = f(T_h)$$



At
 $T_j = 175$ °C

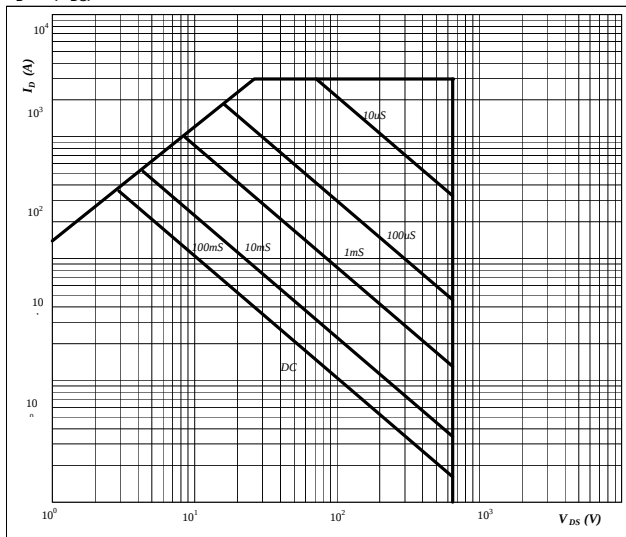
INPUT BOOST

Figure 25

BOOST MOSFET

Safe operating area as a function
of drain-source voltage

$$I_D = f(V_{DS})$$



At

D = single pulse

$T_h = 80$ °C

$V_{GS} = 10$ V

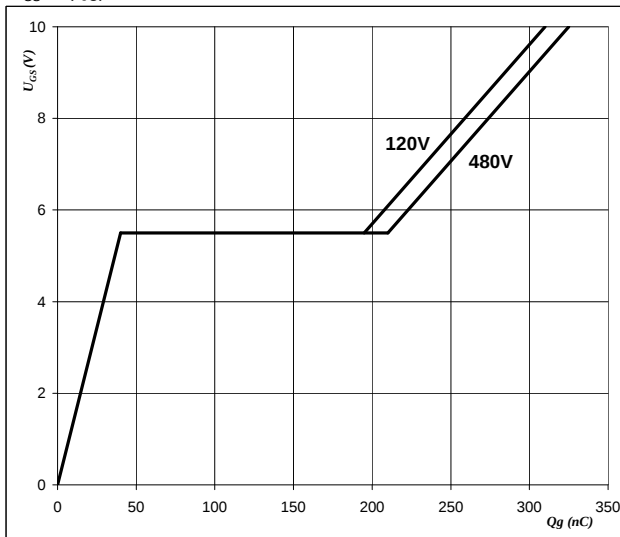
$T_j = T_{jmax}$ °C

Figure 26

BOOST MOSFET

Gate voltage vs Gate charge

$$V_{GS} = f(Q_g)$$



At

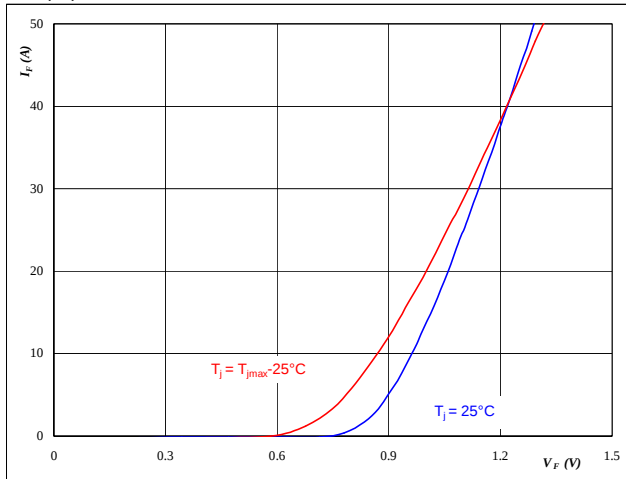
$I_D = 50$ A

Bypass Diode

Figure 1 Bypass diode

Typical diode forward current as a function of forward voltage

$$I_F = f(V_F)$$

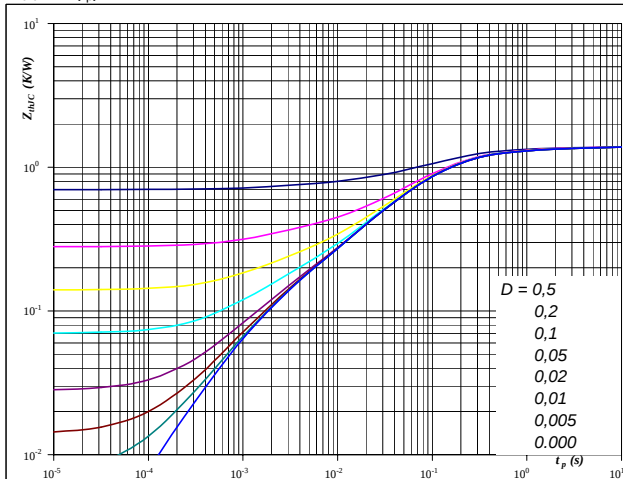


At
 $t_p = 250 \mu s$

Figure 2 Bypass diode

Diode transient thermal impedance as a function of pulse width

$$Z_{thJH} = f(t_p)$$

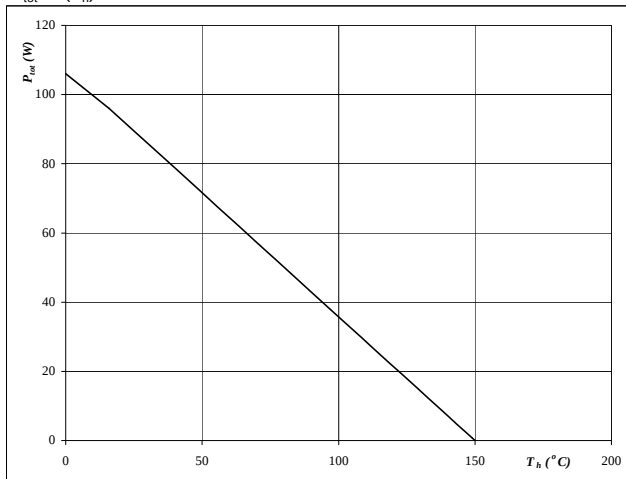


At
 $D = t_p / T$
 $R_{thJH} = 1.397 \text{ K/W}$

Figure 3 Bypass diode

Power dissipation as a function of heatsink temperature

$$P_{tot} = f(T_h)$$

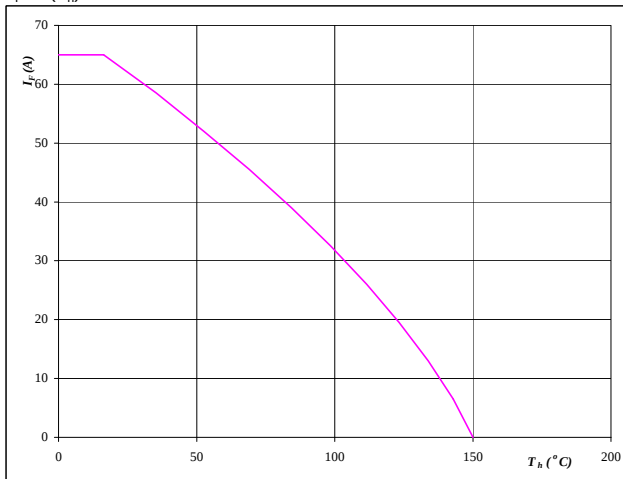


At
 $T_j = 150 \text{ } ^\circ\text{C}$

Figure 4 Bypass diode

Forward current as a function of heatsink temperature

$$I_F = f(T_h)$$



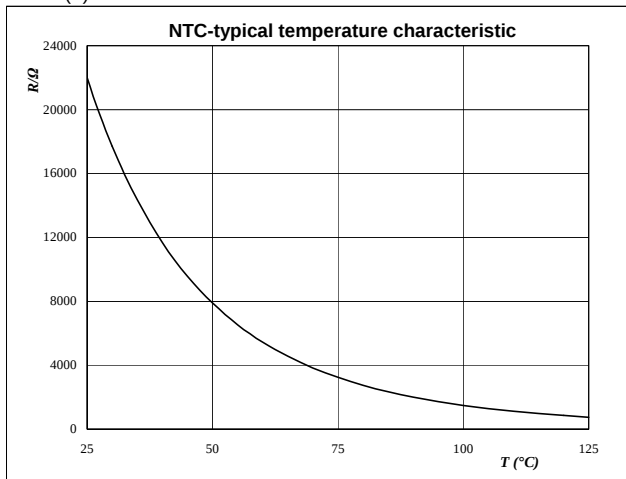
At
 $T_j = 150 \text{ } ^\circ\text{C}$

Thermistor

Figure 1 Thermistor

**Typical NTC characteristic
as a function of temperature**

$$R_T = f(T)$$



Switching Definitions H-Bridge MOSFET

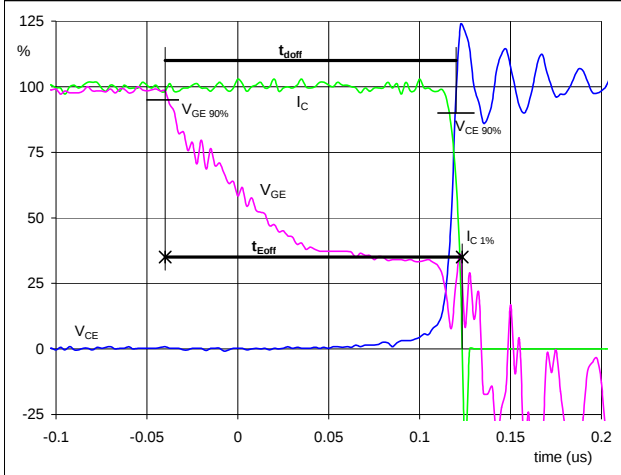
General conditions

T_j	=	125 °C
R_{gon}	=	2 Ω
R_{goff}	=	2 Ω

Figure 1 H-Bridge MOSFET

Turn-off Switching Waveforms & definition of t_{doff} , t_{Eoff}

(t_{Eoff} = integrating time for E_{off})

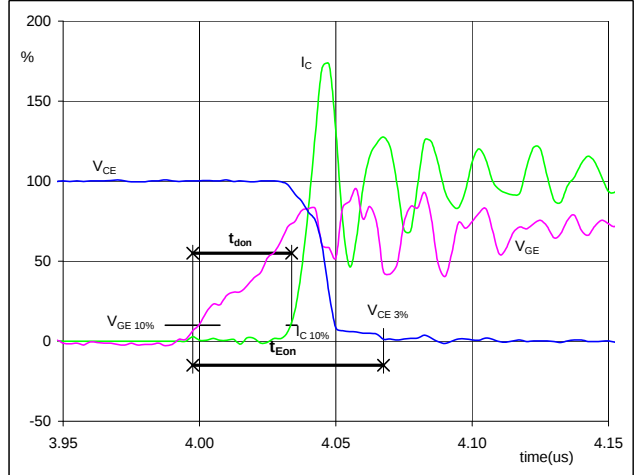


$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	10	V
$V_C(100\%) =$	400	V
$I_C(100\%) =$	30	A
$t_{doff} =$	0.15	μ s
$t_{Eoff} =$	0.16	μ s

Figure 2 H-Bridge MOSFET

Turn-on Switching Waveforms & definition of t_{don} , t_{Eon}

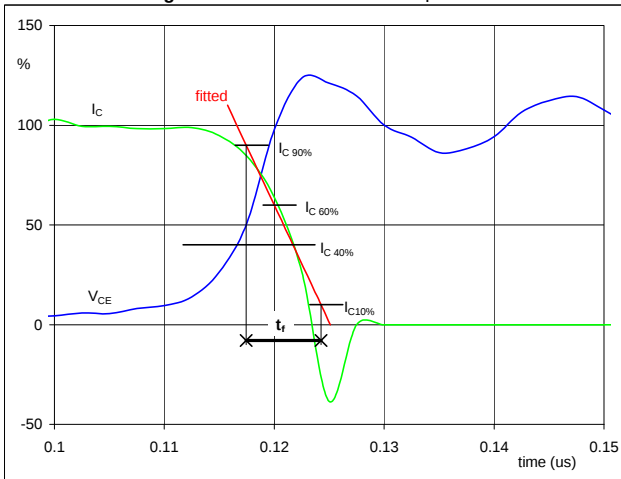
(t_{Eon} = integrating time for E_{on})



$V_{GE}(0\%) =$	0	V
$V_{GE}(100\%) =$	10	V
$V_C(100\%) =$	400	V
$I_C(100\%) =$	30	A
$t_{don} =$	0.04	μ s
$t_{Eon} =$	0.07	μ s

Figure 3 H-Bridge MOSFET

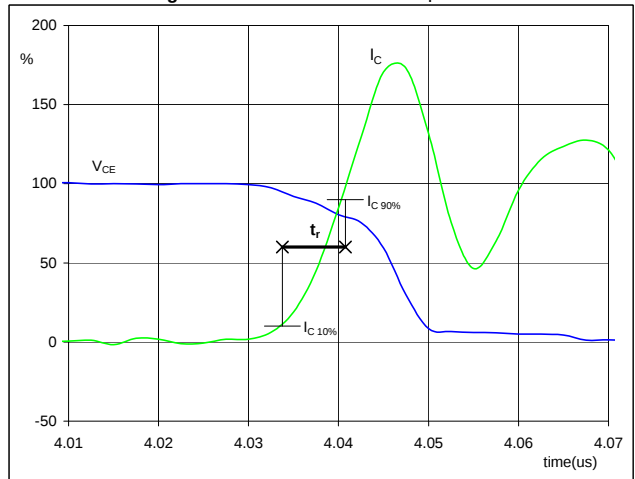
Turn-off Switching Waveforms & definition of t_f



$V_C(100\%) =$	400	V
$I_C(100\%) =$	30	A
$t_f =$	0.01	μ s

Figure 4 H-Bridge MOSFET

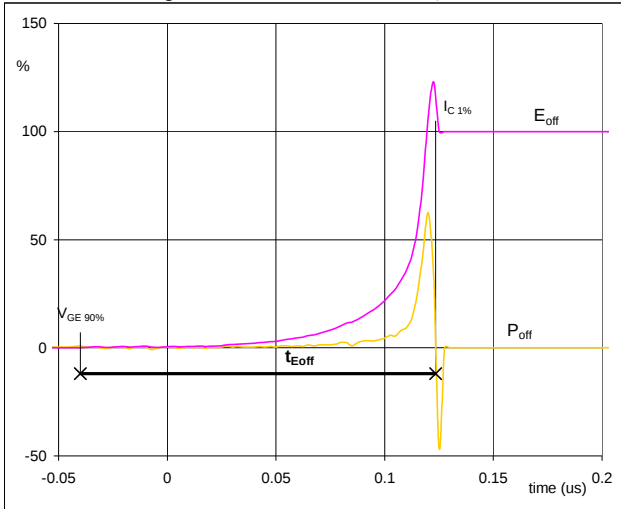
Turn-on Switching Waveforms & definition of t_r



$V_C(100\%) =$	400	V
$I_C(100\%) =$	30	A
$t_r =$	0.01	μ s

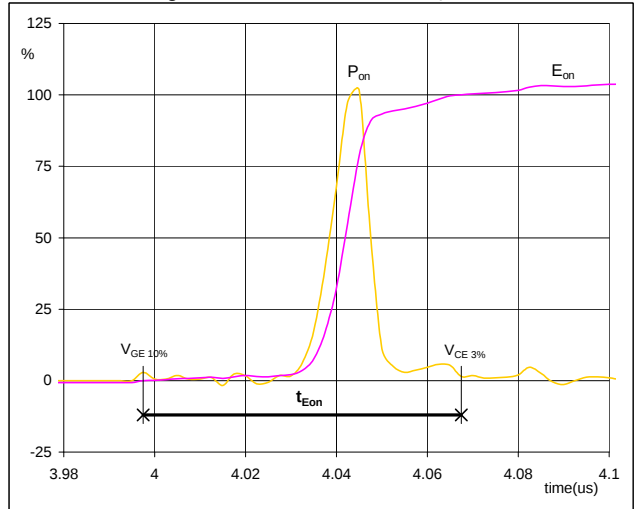
Switching Definitions H-Bridge MOSFET

Figure 5 H-Bridge MOSFET
Turn-off Switching Waveforms & definition of t_{Eoff}



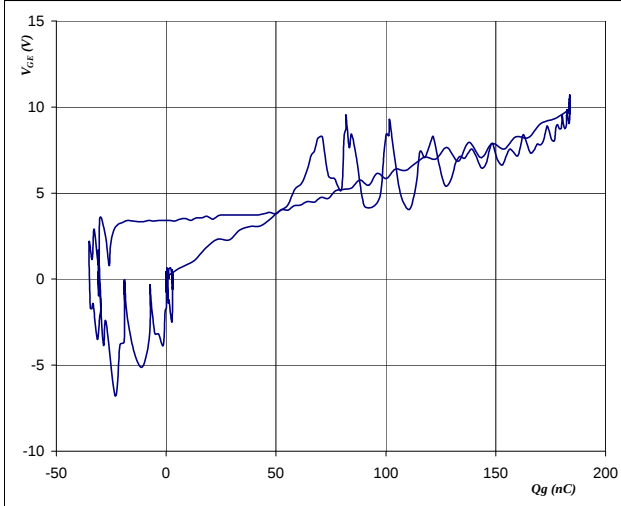
$P_{off} (100\%) = 12.04 \text{ kW}$
 $E_{off} (100\%) = 0.03 \text{ mJ}$
 $t_{Eoff} = 0.16 \text{ }\mu\text{s}$

Figure 6 H-Bridge MOSFET
Turn-on Switching Waveforms & definition of t_{Eon}



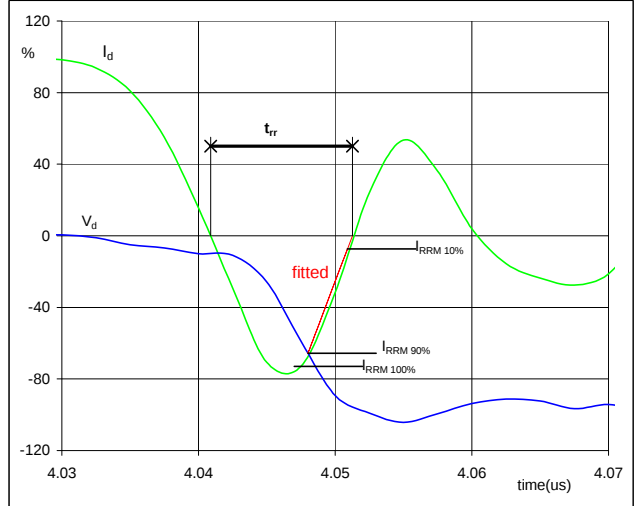
$P_{on} (100\%) = 12.04 \text{ kW}$
 $E_{on} (100\%) = 0.14 \text{ mJ}$
 $t_{Eon} = 0.07 \text{ }\mu\text{s}$

Figure 7 H-Bridge MOSFET
Gate voltage vs Gate charge (measured)



$V_{GEoff} = 0 \text{ V}$
 $V_{GEon} = 10 \text{ V}$
 $V_C (100\%) = 400 \text{ V}$
 $I_C (100\%) = 30 \text{ A}$
 $Q_g = 183.73 \text{ nC}$

Figure 8 H-Bridge FWD
Turn-off Switching Waveforms & definition of t_{rr}

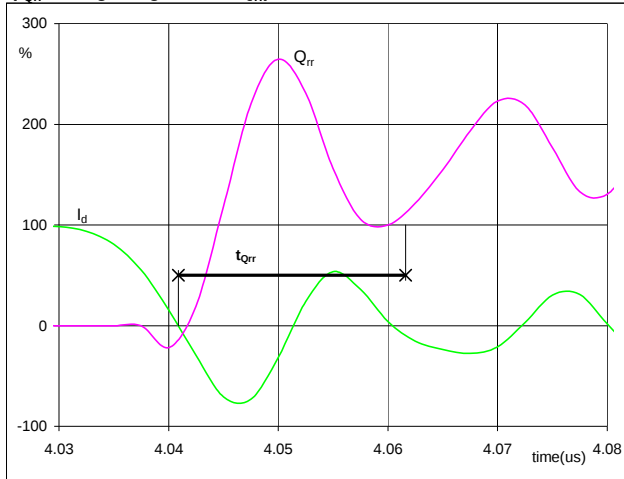


$V_d (100\%) = 400 \text{ V}$
 $I_d (100\%) = 30 \text{ A}$
 $I_{RRM} (100\%) = -24 \text{ A}$
 $t_{rr} = 0.01 \text{ }\mu\text{s}$

Switching Definitions H-Bridge MOSFET

Figure 9 H-Bridge FWD

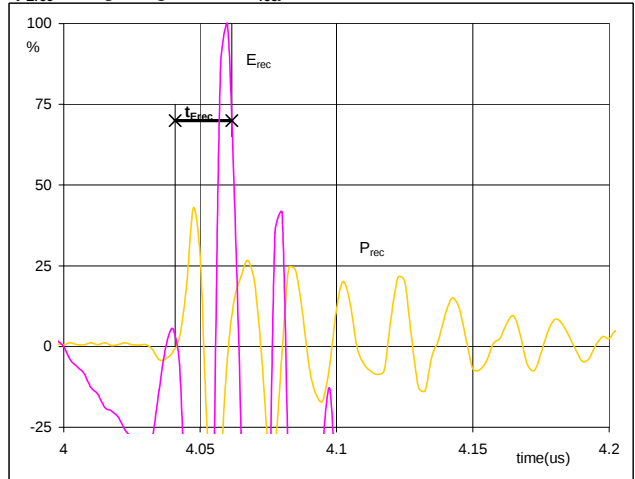
Turn-on Switching Waveforms & definition of t_{Qrr}
(t_{Qrr} = integrating time for Q_{rr})



I_d (100%) = 30 A
 Q_{rr} (100%) = 0.12 μ C
 t_{Qrr} = 0.02 μ s

Figure 10 H-Bridge FWD

Turn-on Switching Waveforms & definition of t_{Erec}
(t_{Erec} = integrating time for E_{rec})



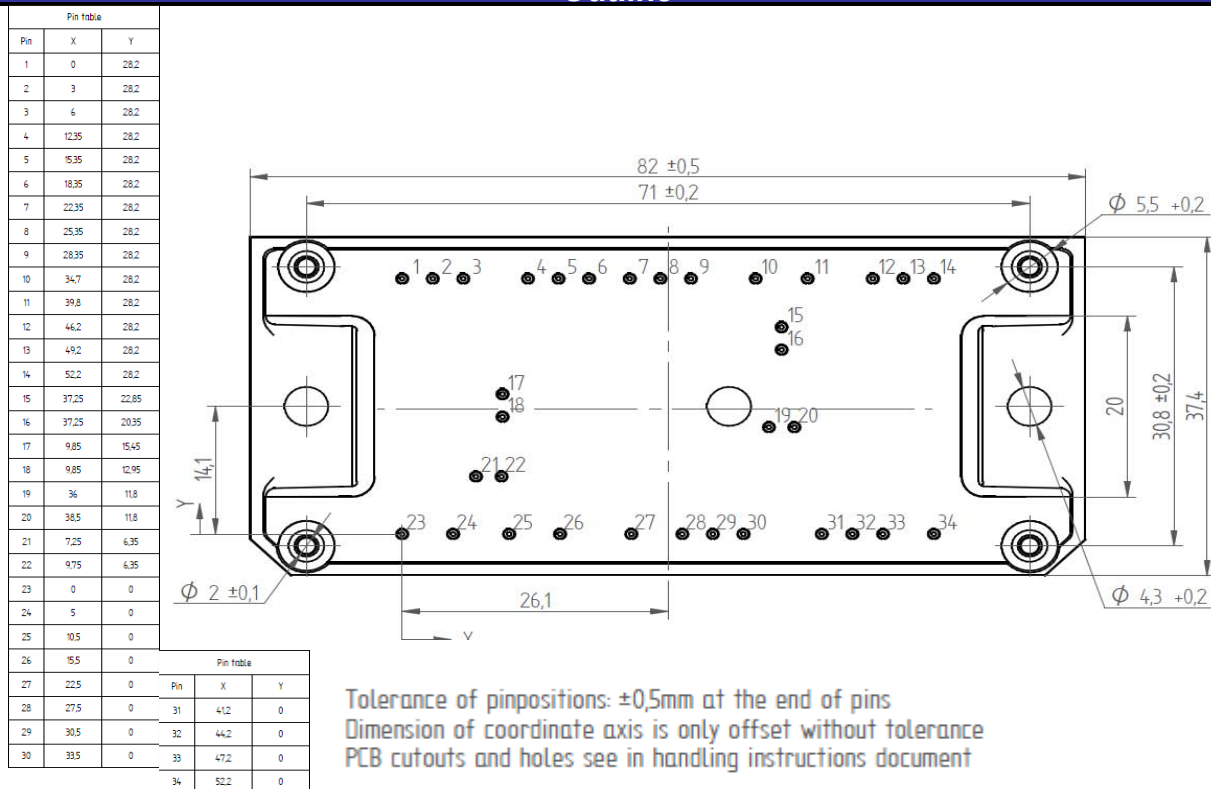
P_{rec} (100%) = 12.04 kW
 E_{rec} (100%) = 0.02 mJ
 t_{Erec} = 0.02 μ s

Ordering Code and Marking - Outline - Pinout

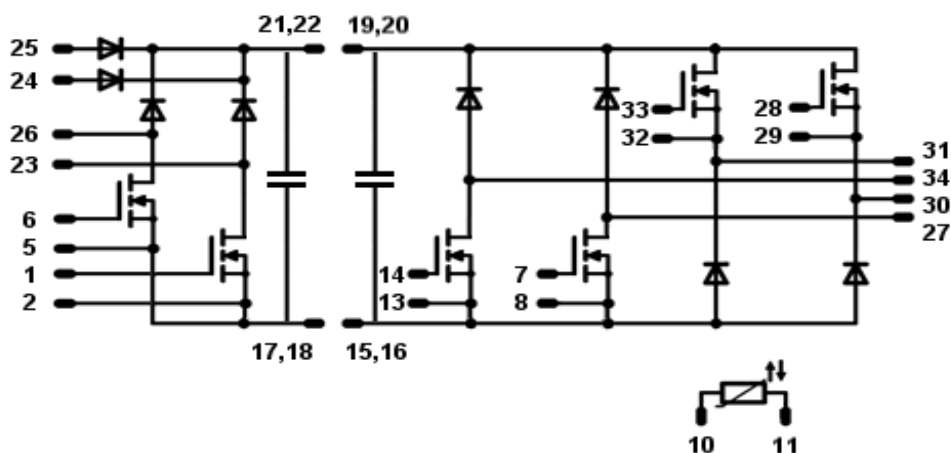
Ordering Code & Marking

Version	Ordering Code	in DataMatrix as	in packaging barcode as
without thermal paste 12mm housing	10-FY07BIA041MC-M528E58	M528E58	M528E58

Outline



Pinout



Pins 3,4,9,12 are not connected.

PRODUCT STATUS DEFINITIONS

Datasheet Status	Product Status	Definition
Target	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice. The data contained is exclusively intended for technically trained staff.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data may be published at a later date. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.
Final	Full Production	This datasheet contains final specifications. Vincotech reserves the right to make changes at any time without notice in order to improve design. The data contained is exclusively intended for technically trained staff.

DISCLAIMER

The information given in this datasheet describes the type of component and does not represent assured characteristics. For tested values please contact Vincotech. Vincotech reserves the right to make changes without further notice to any products herein to improve reliability, function or design. Vincotech does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights, nor the rights of others.

LIFE SUPPORT POLICY

Vincotech products are not authorised for use as critical components in life support devices or systems without the express written approval of Vincotech.

As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in labelling can be reasonably expected to result in significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.